TOSHIBA HIGH EFFICIENCY DIODE STACK (HED) SILICON EPITAXIAL TYPE

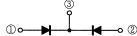
# 16DL2C41A

# SWITCHING MODE POWER SUPPLY APPLICATION **CONVERTER & CHOPPER APPLICATION**

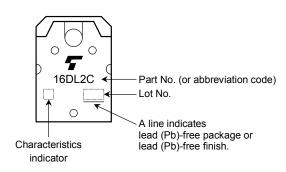
• Repetitive Peak Reverse Voltage : V<sub>RRM</sub>=200V • Average Output Rectified Current : Io=16A • Ultra Fast Reverse-Recovery Time : trr=35ns (Max) • Low Forward Voltage : V<sub>FM</sub>=0.98V (Max)

Low Switching Losses and Output Noise

# **POLARITY**



#### **MARKING**



Unit in mm
Unit in mm  43.2±0.2  3.3 MAX.  40.1  1. ANODE  2. ANODE  2. ANODE  3. CATHODE (CASE)
JEDEC —
JEITA —
TOSHIBA 12-16D1A

Weight: 4.85g

Abbreviation Code	Part No.
16DL2C	16DL2C41A

#### **MAXIMUM RATINGS**

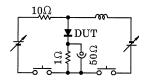
CHARACTERISTIC	SYMBOL	RATING	UNIT	
Repetitive Peak Reverse Voltage	$V_{RRM}$	200	V	
Average Output Rectified Current (Full Sine Waveform)	IO	16	Α	
Peak One Cycle Surge Forward Current (Non-Repetitive)	I <sub>FSM</sub>	80 (50H <sub>Z</sub> )	A	
		88 (60H <sub>Z</sub> )		
Junction Temperature	Тј	-40~150	°C	
Strage Temperature Range	T <sub>stg</sub>	-40~150	°C	

# ELECTRICAL CHARACTERISTICS (Ta=25°C) (Note 1)

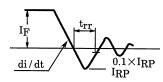
		, , , , , , , , , , , , , , , , , , , ,			
CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	MAX.	UNIT
Peak Forward Voltage	$V_{FM}$	I <sub>FM</sub> =8A	_	0.98	V
Repetitive Peak Reverse Current	I <sub>RRM</sub>	V <sub>RRM</sub> =Rated	_	50	μA
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> =2.0A di / dt=-50A / μs (Note 2)	_	35	ns
Forward Recovery Time	t <sub>fr</sub>	I <sub>F</sub> =1.0A (Note 3)	_	100	ns
Thermal Resistance	R <sub>th (j-c)</sub>	Total DC, Junction to Case	_	1.9	°C/W

Note 1: A value applied to one cell.

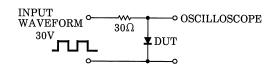
Note 2: t<sub>rr</sub> Test circuit



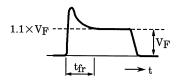
trr Waveform



Note 3: tfr Test circuit



tfr Waveform



# **Handling Precaution**

The maximum ratings denote the absolute maximum ratings, which are rated values and must not be exceeded during operation, even for an instant. The following are the general derating methods that we recommend when you design a circuit with a device.

VRRM: We recommend that the worst case voltage, including surge voltage, be no greater than 80% of the maximum rating of VRRM for a DC circuit and be no greater than 50% of that of VRRM for an AC circuit. VRRM has a temperature coefficient of 0.1%/°C. Take this temperature coefficient into account designing a device at low temperature.

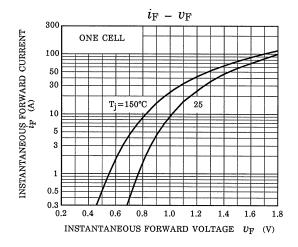
IO: We recommend that the worst case current be no greater than 80% of the maximum rating of Io. Carry out adequate heat design. If you can't design a circuit with excellent heat radiation, set the margin by using an allowable Tamax-Io curve.

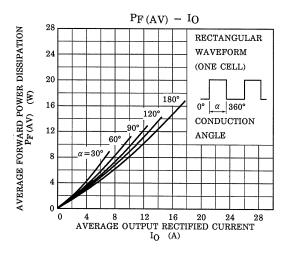
This rating specifies the non-repetitive peak current in one cycle of a 50-Hz sine wave, condition angle 180. Therefore, this is only applied for an abnormal operation, which seldom occurs during the lifespan of the device.

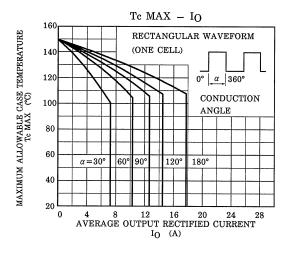
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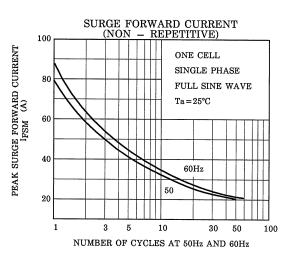
We recommend that a device be used at a Tj of below  $120^{\circ}$ C under the worst load and heat radiation conditions.

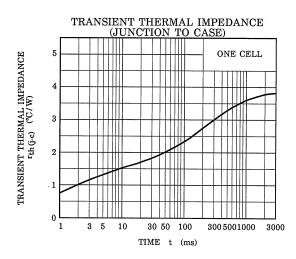
Please refer to the Rectifiers databook for further information.

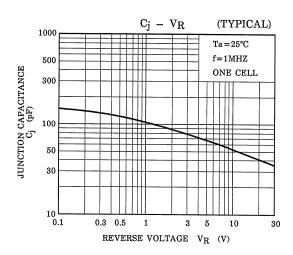












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